

## P-Channel Enhancement Mode Power MOSFET

#### **DESCRIPTION**

The HM2341B uses advanced trench technology to provide excellent  $R_{\rm DS(ON)}$ , low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a load switch or in PWM applications.

#### **GENERAL FEATURES**

•  $V_{DS} = -30V, I_{D} = -4.2A$ 

 $R_{DS(ON)}$  < 130m $\Omega$  @  $V_{GS}$ =-2.5V

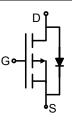
 $R_{DS(ON)}$  < 75m $\Omega$  @  $V_{GS}$ =-4.5V

 $R_{DS(ON)}$  < 65m $\Omega$  @  $V_{GS}$ =-10V

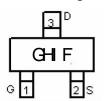
- High Power and current handing capability
- Lead free product is acquired
- Surface Mount Package

# **Application**

- PWM applications
- Load switch
- Power management



Schematic diagram



Marking and pin Assignment



SOT-23 top view

## **Package Marking And Ordering Information**

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
2341	HM2341B	SOT-23	Ø180mm	8 mm	3000 units

#### Absolute Maximum Ratings (TA=25℃unless otherwise noted)

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V <sub>DS</sub>	-30	V	
Gate-Source Voltage	V <sub>GS</sub>	±12	V	
Drain Current-Continuous	I <sub>D</sub>	-4.2	Α	
Drain Current-Pulsed (Note 1)	I <sub>DM</sub>	-30	Α	
Maximum Power Dissipation	P <sub>D</sub>	1.2	W	
Operating Junction and Storage Temperature Range	$T_{J}, T_{STG}$	-55 To 150	°C	

#### **Thermal Characteristic**

Thermal Resistance, Junction-to-Ambient (Note 2)	R <sub>0JA</sub>	104	°C/W
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## Electrical Characteristics (TA=25℃ unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =-250μA	-30		-	٧
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =-24V,V <sub>GS</sub> =0V	-	-	-1	μΑ

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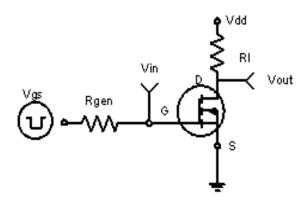
**Page 1** v1.1

$ Por inn-Source On-State Resistance & R_{DS(ON)} & V_{GS}=-10V, I_D=-4.2A & - & 50 & 55 & mm \\ V_{GS}=-2.5V, I_D=-4A & - & 64 & 72 & mm \\ V_{GS}=-2.5V, I_D=-1A & - & 95 & 120 & mm \\ V_{DS}=-2.5V, I_D=-4.2A & - & 10 & - & 80 \\ \hline Por inner Characteristics (Note4) & & & & & & & & & & & & & & & & & & &$	Gate-Body Leakage Current	I <sub>GSS</sub>	$V_{GS}$ =±12 $V$ , $V_{DS}$ =0 $V$	-	-	±100	nA
$ Parameter (a) = 0 \  \  \  \  \  \  \  \  \  \  \  \  \$	On Characteristics (Note 3)						
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> ,I <sub>D</sub> =-250μA	-0.7	-1	-1.3	V
			V <sub>GS</sub> =-10V, I <sub>D</sub> =-4.2A	-	50	55	mΩ
Forward Transconductance   gFS   V_DS=-5V, I_D=-4.2A   - 10   -   S	Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-4A	-	64	72	mΩ
Dynamic Characteristics (Note4)			V <sub>GS</sub> =-2.5V, I <sub>D</sub> =-1A		95	120	mΩ
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Forward Transconductance	<b>g</b> FS	V <sub>DS</sub> =-5V,I <sub>D</sub> =-4.2A	-	10	-	S
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Dynamic Characteristics (Note4)						
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Input Capacitance	C <sub>lss</sub>	\/ - 15\/\/ -0\/	-	950	-	PF
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Output Capacitance	C <sub>oss</sub>		-	115	-	PF
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Reverse Transfer Capacitance	C <sub>rss</sub>	F = 1.0IVII 12	-	75	-	PF
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Switching Characteristics (Note 4)						
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Turn-on Delay Time	t <sub>d(on)</sub>		-	7	-	nS
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Turn-on Rise Time	t <sub>r</sub>	V <sub>DD</sub> =-15V,I <sub>D</sub> =-3.2A	-	3	-	nS
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS}$ =-10 $V$ , $R_{GEN}$ =6 $\Omega$	-	30	-	nS
	Turn-Off Fall Time	t <sub>f</sub>		-	12	-	nS
Gate-Drain Charge Q <sub>gd</sub> - 3 - n  Drain-Source Diode Characteristics	Total Gate Charge	Qg		-	9.5	-	nC
Drain-Source Diode Characteristics	Gate-Source Charge	Q <sub>gs</sub>	V <sub>DS</sub> =-15V,I <sub>D</sub> =-4A,V <sub>GS</sub> =-4.5V	-	2	-	nC
	Gate-Drain Charge	$Q_{gd}$		-	3	-	nC
Diodo Forward Voltago (Noto 3)	Drain-Source Diode Characteristics	·					
Diduce Foliward Voltage (Note 3) VSD VGS-UV,IS-TIA 1.2	Diode Forward Voltage (Note 3)	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =-1A	-	-	-1.2	V

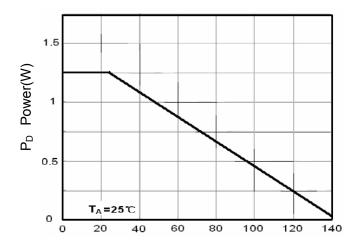
#### Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- 3. Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to production

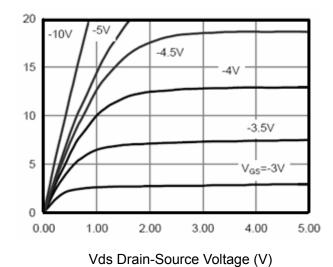
## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



**Figure 1:Switching Test Circuit** 



 $T_J$ -Junction Temperature (°C) **Figure 3 Power Dissipation** 



I<sub>D</sub>- Drain Current (A)

Figure 5 Output CHARACTERISTICS

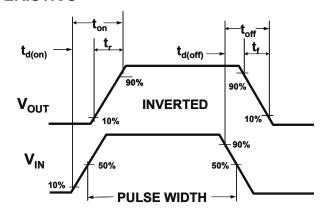


Figure 2:Switching Waveforms

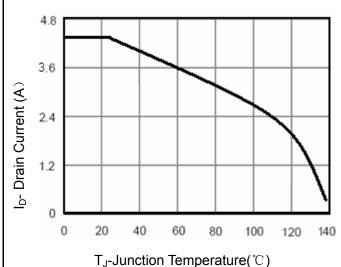


Figure 4 Drain Current

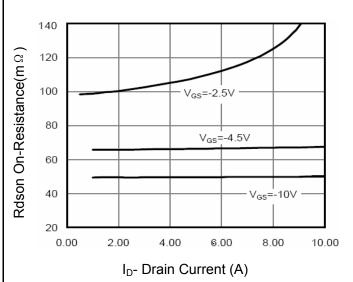
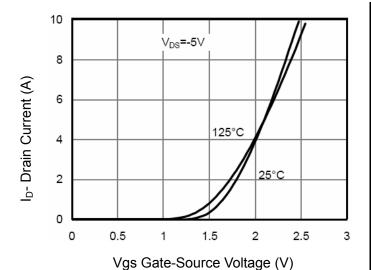


Figure 6 Drain-Source On-Resistance

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Page 3 v1.1



**Figure 7 Transfer Characteristics** 

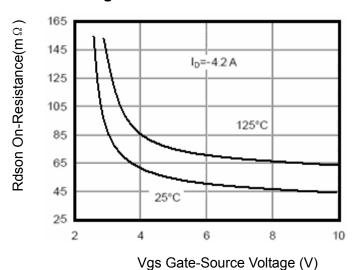


Figure 9 Rdson vs Vgs

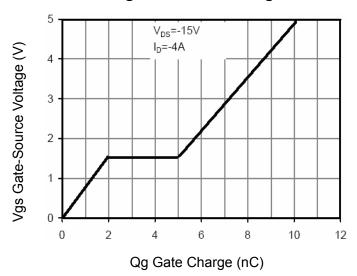
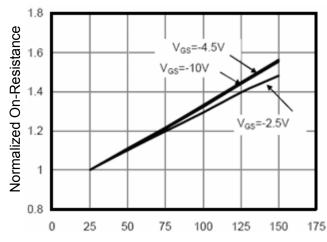
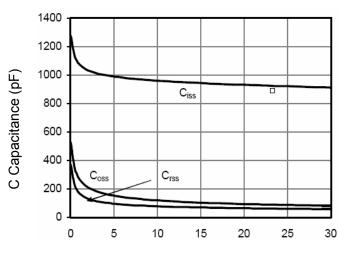


Figure 11 Gate Charge



T<sub>J</sub>-Junction Temperature(°C)





Vds Drain-Source Voltage (V)

Figure 10 Capacitance vs Vds

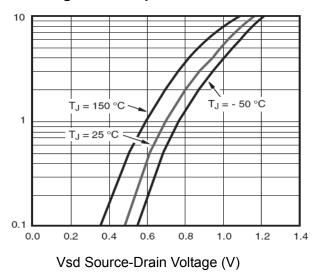


Figure 12 Source- Drain Diode Forward

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Is- Reverse Drain Current (A)

Page 4 v1.1

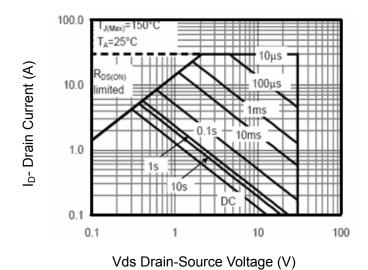
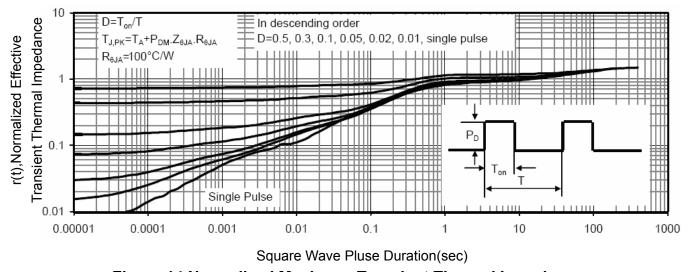


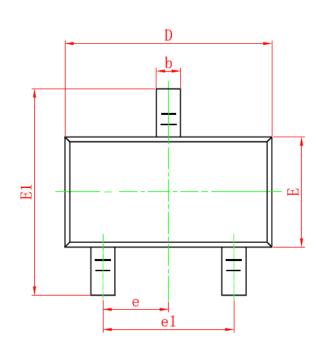
Figure 13 Safe Operation Area

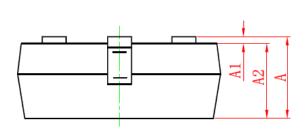


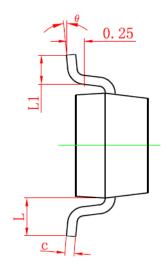
**Figure 14 Normalized Maximum Transient Thermal Impedance** 

# **SOT-23 PACKAGE INFORMATION**









Symbol	Dimensions in Millimeters			
Symbol	MIN.	MAX.		
Α	0.900	1.150		
<b>A</b> 1	0.000	0.100		
A2	0.900	1.050		
b	0.300	0.500		
С	0.080	0.150		
D	2.800	3.000		
E	1.200	1.400		
E1	2.250	2.550		
е	0.950TYP			
e1	1.800	2.000		
L	0.550REF			
L1	0.300	0.500		
θ	0°	8°		

## **NOTES**

- 1. All dimensions are in millimeters.
- 2. Tolerance ±0.10mm (4 mil) unless otherwise specified
- 3. Package body sizes exclude mold flash and gate burrs. Mold flash at the non-lead sides should be less than 5 mils.
- 4. Dimension L is measured in gauge plane.
- $5. \ Controlling \ dimension \ is \ millimeter, \ converted \ inch \ dimensions \ are \ not \ necessarily \ exact.$

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